Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination FRITZ ET AL. | Examiner | Art Unit | Page 1 of 1

U.S. PATENT DOCUMENTS

*	·	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0043404	03-2003	Fetherolf et al.	358/1.15
*	В	US-2004/0150803	08-2004	Boldon, John Leland	355/018
*	С	US-2001/0005269	06-2001	Nozawa, Shinji	358/1.12
*	D	US-2002/0105663	08-2002	Pappalardo et al.	358/1.12
*	Ε	US-2002/0131065	09-2002	Sweetland et al.	358/1.13
*	F	US-6,493,743	12-2002	Suzuki, Hideo	709/203
*	G	US-7,173,724	02-2007	Nomura et al.	358/1.15
*	н	US-6,781,709	08-2004	Nozawa, Shinji	358/1.12
*	ı	US-6,934,915	08-2005	Rudd et al.	715/765
*	J	US-7,065,562	06-2006	Courtney, Mike	709/220
*	K	US-6,959,329	10-2005	Thakor, Sanjiv	709/220
*	L	US-6,674,537	01-2004	Kadowaki, Toshihiro	358/1.15
*	М	US-2004/0012628	01-2004	Kropf et al.	345/744

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0				·	
	Р					
	Q		_			
	R					
	s					
	Т				·	

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	×	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.